

# Low Skew, 1-to-16 LVCMOS/LVTTL Clock Generator

**DATASHEET** 

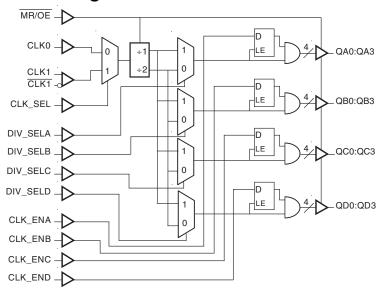
# **Description**

The ICS87016I is a low skew, 1:16 LVCMOS/LVTTL Clock Generator. The device has four banks of four outputs and each bank can be independently selected for  $\div 1$  or  $\div 2$  frequency operation. Each bank also has its own power supply pins so that the banks can operate at the following different voltage levels: 3.3V, 2.5V, and 1.8V. The low impedance LVCMOS/LVTTL outputs are designed to drive  $50\Omega$  series or parallel terminated transmission lines.

The divide select inputs, DIV\_SELA:DIV\_SELD, control the output frequency of each bank. The output banks can be independently selected for  $\div 1$  or  $\div 2$  operation. The bank enable inputs, CLK\_ENA:CLK\_END, support enabling and disabling each bank of outputs individually. The CLK\_ENA:CLK\_END circuitry has a synchronizer to prevent runt pulses when enabling or disabling the clock outputs. The master reset input,  $\overline{\text{MR/OE}}$ , resets the  $\div 1/\div 2$  flip flops and also controls the active and high impedance states of all outputs. This pin has an internal pull-up resistor and is normally used only for test purposes or in systems which use low power modes.

The ICS87016I is characterized to operate with the core at 3.3V or 2.5V and the banks at 3.3V, 2.5V, or 1.8V. Guaranteed bank, output, and part-to-part skew characteristics make the 87016I ideal for those clock applications demanding well-defined performance and repeatability.

# **Block Diagram**



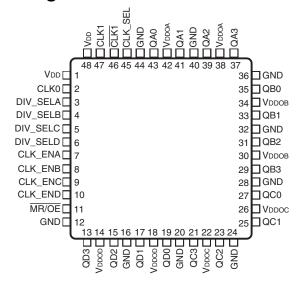
#### **Features**

- Sixteen LVCMOS/LVTTL outputs (4 banks of 4 outputs)
- Selectable differential CLK1/CLK1 or LVCMOS/LVTTL clock input
- CLK1, CLK1 pair can accept the following differential input levels: LVPECL, LVDS, LVHSTL, SSTL, HCSL
- CLK0 supports the following input types: LVCMOS, LVTTL
- Maximum output frequency: 250MHz
- Independent bank control for ÷1 or ÷2 operation
- Independent output bank voltage settings for 3.3V, 2.5V, or 1.8V operation
- Asynchronous clock enable/disable
- Output skew: 170ps (maximum)
- Bank skew: 50ps (maximum
- Part-to-Part Skew: 800ps (maximum)
- Supply modes: Core/Output 3.3V/3.3V 3.3V/2.5V 3.3V/1.8V 2.5V/2.5V 2.5V/1.8V

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- -40°C to 85°C ambient operating temperature
- Lead-free packaging

# **Pin Assignment**



#### ICS87016I

48-Lead LQFP 7mm x 7mm x 1.4mm package body Y Package Top View

**Table 1. Pin Descriptions** 

Number	Name	Ty	<sub>/pe</sub>	Description
1, 48	$V_{DD}$	Power		Positive supply pins.
2	CLK0	Input	Pulldown	Single-ended clock input. LVCMOS/LVTTL interface levels.
3	DIV_SELA	Input	Pullup	Controls frequency division for Bank A outputs. See Table 3. LVCMOS / LVTTL interface levels.
4	DIV_SELB	Input	Pullup	Controls frequency division for Bank B outputs. See Table 3. LVCMOS / LVTTL interface levels.
5	DIV_SELC	Input	Pullup	Controls frequency division for Bank C outputs. See Table 3. LVCMOS / LVTTL interface levels.
6	DIV_SELD	Input	Pullup	Controls frequency division for Bank D outputs. See Table 3. LVCMOS / LVTTL interface levels.
7	CLK_ENA	Input	Pullup	Output enable for Bank A outputs. Active HIGH. If pin is LOW, outputs drive low. LVCMOS/LVTTL interface levels. See Table 3.
8	CLK_ENB	Input	Pullup	Output enable for Bank A outputs. Active HIGH. If pin is LOW, outputs drive low. LVCMOS/LVTTL interface levels. See Table 3.
9	CLK_ENC	Input	Pullup	Output enable for Bank A outputs. Active HIGH. If pin is LOW, outputs drive low. LVCMOS/LVTTL interface levels. See Table 3.
10	CLK_END	Input	Pullup	Output enable for Bank A outputs. Active HIGH. If pin is LOW, outputs drive low. LVCMOS/LVTTL interface levels. See Table 3.
11	MR/OE	Input	Pullup	Master reset. When LOW, resets the ÷1/÷2 flip flops and sets the outputs to high impedance. LVCMOS / LVTTL interface levels.
12, 16, 20, 24, 28, 32, 36, 40, 44	GND	Power		Power supply ground
13, 15, 17, 19	QD3, QD2, QD1, QD0	Output		Bank D single-ended clock outputs. LVCMOS/LVTTL interface levels.
14, 18	$V_{DDOD}$	Power		Bank D output supply pins.
21, 23, 25, 27	QC3, QC2, QC1, QC0	Output		Bank C single-ended clock outputs. LVCMOS/LVTTL interface levels.
22, 26	$V_{DDOC}$	Power		Bank C output supply pins.
29, 31, 33, 35	QB3, QB2, QB1, QB0	Output		Bank C single-ended clock outputs. LVCMOS/LVTTL interface levels.
30, 34	$V_{DDOB}$	Power		Bank B output supply pins.
37, 39, 41, 43	QA3, QA2, QA1, QA0	Output		Bank A single-ended clock outputs. LVCMOS/LVTTL interface levels.
38, 42	$V_{DDOA}$	Power		Bank B output supply pins.
45	CLK_SEL	Input	Pulldown	Clock select input. When HIGH, selects CLK1, CLK1 inputs. When LOW, selects CLK0 input. LVCMOS / LVTTL interface levels.
46	CLK1	Input	Pullup	Inverting differential clock input.
47	CLK1	Input	Pulldown	Non-inverting differential clock input.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

**Table 2. Pin Characteristics** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			4		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			51		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			51		kΩ
		$V_{DD,} V_{DDOx} = 3.465V$			18	pF
		V <sub>DD</sub> , V <sub>DDOx</sub> = 2.625V			12	pF
C <sub>PD</sub>	Power Dissipation Capacitance	$V_{DD} = 3.465V,$ $V_{DDOx} = 2.625V$			20	pF
ОРД	(per output); NOTE 1	$V_{DD} = 3.465V,$ $V_{DDOx} = 1.89V$			30	pF
		$V_{DD} = 2.625V,$ $V_{DDOx} = 1.89V$			14	pF
R <sub>OUT</sub>	Output Impedance		5	7	12	Ω

NOTE 1:  $V_{DDOx}$  denotes  $V_{DDOA}$ ,  $V_{DDOB}$ ,  $V_{DDOC}$ ,  $V_{DDOD}$ .

# **Function Tables**

**Table 3. Function Table** 

	Inputs	Outputs		
MR/OE	CLK_ENx	DIV_SELx	Bank [A:D]	Qx Frequency
0	Х	Х	Hi-Z	N/A
1	1	0	Active	fIN/2
1	1	1	Active	fIN
1	0	Х	LOW	N/A

# **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>CC</sub>	4.6V
Inputs, V <sub>I</sub>	-0.5V to V <sub>DD</sub> + 0.5V
Outputs, V <sub>O</sub>	-0.5V to V <sub>DD Ox</sub> + 0.5V
Package Thermal Impedance, $\theta_{JA}$	47.9°C/W (0 lfpm)
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C

### **DC Electrical Characteristics**

Table 4A. Power Supply DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDOx} = 3.3V \pm 5\%$ ,  $2.5V \pm 5\%$ ,  $1.8V \pm 5\%$ ,  $T_A = -40$ °C to 85°C to 85

Symbol	Parameter	<b>Test Conditions</b>	Minimum	Typical	Maximum	Units
$V_{DD}$	Positive Supply Voltage		3.135	3.3	3.465	٧
V <sub>DDOA</sub> , V <sub>DDOB</sub> ,			3.135	3.3	3.465	٧
	Output Supply Voltage		2.375	2.5	2.625	V
V <sub>DDOC,</sub> V <sub>DDOD</sub>			1.71	1.8	1.89	٧
I <sub>DD</sub>	Power Supply Current				100	mA
I <sub>DDOA</sub> , I <sub>DDOB</sub> , I <sub>DDOC</sub> , I <sub>DDOD</sub>	Output Supply Current				15	mA

Table 4B. Power Supply DC Characteristics,  $V_{DD} = 2.5V \pm 5\%$ ,  $V_{DDOx} = 2.5V \pm 5\%$ ,  $1.8V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$ 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>DD</sub>	Positive Supply Voltage		2.375	2.5	2.625	V
V <sub>DDOA</sub> , V <sub>DDOB</sub> , V <sub>DDOC</sub> , V <sub>DDOD</sub>			2.375	2.5	2.625	V
	Output Supply Voltage		1.71	1.8	1.89	٧
I <sub>DD</sub>	Power Supply Current				95	mA
I <sub>DDOA</sub> , I <sub>DDOB</sub> , I <sub>DDOC</sub> , I <sub>DDOD</sub>	Output Supply Current				8	mA

Table 4C. LVCMOS/LVTTL DC Characteristics,  $T_A = -40$  °C to 85 °C

Symbol	Paramete	r	Test Conditions	Minimum	Typical	Maximum	Units
V	Input High	Voltago	V <sub>DD</sub> = 3.465V	2		V <sub>DD</sub> + 0.3	V
V <sub>IH</sub>	input nigh	Voltage	V <sub>DD</sub> = 2.625V	1.7		V <sub>DD</sub> + 0.3	V
V	Input Low	Voltago	V <sub>DD</sub> = 3.465V	-0.3		0.8	V
V <sub>IL</sub>	Input Low	voltage	V <sub>DD</sub> = 2.625V	-0.3		0.7	V
	Input	CLK0, CLK_SEL	V <sub>DD</sub> = V <sub>IN</sub> = 3.465V or 2.625V			150	μΑ
I <sub>IH</sub>	High Current	CLK_EN[A:D], DIV_SEL[A:D], MR/OE	V <sub>DD</sub> = V <sub>IN</sub> = 3.465V or 2.625V			5	μА
	Innut	CLK0, CLK_SEL	V <sub>DD</sub> = 3.465V or 2.625V, V <sub>IN</sub> = 0V	-5			μA
I <sub>IL</sub>	Input Low Current	CLK_EN[A:D], DIV_SEL[A:D], MR/OE	V <sub>DD</sub> = 3.465V or 2.625V, V <sub>IN</sub> = 0V	-150			μΑ
			$V_{DDOx} = 3.3V \pm 5\%$	2.6			V
V <sub>OH</sub>		gh Voltage;	$V_{DDOx} = 2.5V \pm 5\%$	1.8			V
OH	NOTE 1		$V_{DDOx} = 1.8V \pm 5\%;$ $I_{OH} = -2mA$	V <sub>DDOx</sub> - 0.45			V
			$V_{DDOx} = 3.3V \pm 5\%$			0.5	V
$V_{OL}$	Output Lov	w Voltage;	$V_{DDOx} = 2.5V \pm 5\%$			0.5	V
· OL	NOTE 1		$V_{DDOx} = 1.8V \pm 5\%;$ $I_{OH} = 2mA$			0.45	V
I <sub>OZL</sub>	Output Hi-Z Current Low			-5			μA
I <sub>OZH</sub>	Output Hi-	Z Current High				5	μA

NOTE 1: Outputs terminated with  $50\Omega$  to  $V_{DDOX}/2$ . See Parameter Measurement Information, Output Load Test Circuit diagrams.

Table 4D. Differential DC Characteristics,  $T_A = -40 \,^{\circ}\text{C}$  to  $85 \,^{\circ}\text{C}$ 

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
I <sub>IH</sub>	Input High Current	CLK1	$V_{DD} = V_{IN} = 3.465 V \text{ or } 2.625 V$			5	μA
	input riigh Current	CLK1	$V_{DD} = V_{IN} = 3.465 V \text{ or } 2.625 V$			150	μΑ
	Input Low Current	CLK1	V <sub>DD</sub> = 3.465V or 2.625V, V <sub>IN</sub> = 0V	-150			μΑ
<sup>l</sup> l∟	input Low Current	CLK1	V <sub>DD</sub> = 3.465V or 2.625V, V <sub>IN</sub> = 0V	-5			μA
V <sub>PP</sub>	Peak-to-Peak Voltage			0.15		1.3	V
V <sub>CMR</sub>	Common Mode Input Voltage; NOTE 1, 2	t		GND + 0.5		V <sub>DD</sub> – 0.85	V

NOTE 1: Common mode input voltage is defined as  $V_{IH}$ . NOTE 2: For single-ended applications, the maximum input voltage for CLK1,  $\overline{\text{CLK1}}$  is  $V_{DD}$  + 0.3V.

### **AC Electrical Characteristics**

Table 5A. AC Characteristics,  $V_{DD} = V_{DDOx} = 3.3V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$ 

Parameter	Symbol		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Freque	ency				250	MHz
tp <sub>LH</sub>	Propagation	CLK0; NOTE 1A		2.8	3.4	3.9	ns
	Delay, Low to High	CLK1/CLK1; NOTE 1B		2.75	3.4	4.1	ns
tsk(b)	Bank Skew; NOTE 2, 6		Measured on the Rising Edge			50	ps
tsk(o)	Output Skew; NOTE 3, 6		Measured on the Rising Edge			170	ps
tsk(pp)	Part-to-Part Skew; NOTE 4, 6					800	ps
$t_R / t_F$	Output Rise/Fall Time; NOTE 5		20% to 80%	200		700	ps
	Outrout Duty C	S1-	<i>f</i> < 175MHz	45		55	%
odc	Output Duty C	ycie	<i>f</i> ≥ 175MHz	40		60	%
t <sub>EN</sub>	Output Enable Time; NOTE 5					10	ns
t <sub>DIS</sub>	Output Disable Time; NOTE 5					10	ns

All parameters measured at 250MHz unless noted otherwise.

NOTE 1A: Measured from the  $V_{DD}/2$  of the input to  $V_{DDOX}/2$  of the output.

NOTE 1B: Measured from the differential input crossing point to  $V_{DDOX}/2$  of the output.

NOTE 2: Defined as skew within a bank with equal load conditions.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at V<sub>DDOX</sub>/2.

NOTE 4: Defined as skew between outputs on different devices operating a the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at  $V_{DDOX}/2$ .

NOTE 5: These parameters are guaranteed by characterization. Not tested in production.

NOTE 6: This parameter is defined in accordance with JEDEC Standard 65.

**Table 5B. AC Characteristics,**  $V_{DD} = V_{DDOx} = 2.5V \pm 5\%$ ,  $T_A = -40$ °C to 85°C

Parameter	Symbol		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Frequency					250	MHz
tp <sub>LH</sub>	Propagation CLK0; NOTE 1A			2.9	3.8	4.7	ns
	Delay, Low to High	CLK1/CLK1; NOTE 1B		3.0	3.6	4.3	ns
tsk(b)	Bank Skew; NOTE 2, 6		Measured on the Rising Edge			70	ps
tsk(o)	Output Skew;	NOTE 3, 6	Measured on the Rising Edge			210	ps
tsk(pp)	Part-to-Part S	kew; NOTE 4, 6				800	ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time; NOTE 5		20% to 80%	150		700	ps
odc	Output Duty C	Cycle	<i>f</i> ≤ 125MHz	40		60	%
t <sub>pw</sub>	Output Pulse Width		f> 125MHz	t <sub>Period</sub> /2 - 800		t <sub>Period</sub> /2 + 800	ps
t <sub>EN</sub>	Output Enable Time; NOTE 5					10	ns
t <sub>DIS</sub>	Output Disable	e Time; NOTE 5				10	ns

For NOTES, please see above, Table 5A.

Table 5C. AC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDOx} = 2.5V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$ 

Parameter	Symbol		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Freque	ncy				250	MHz
tp <sub>LH</sub>	Propagation	CLK0; NOTE 1A		2.9	3.5	4.0	ns
	LOW TO LITUIT	CLK1/CLK1; NOTE 1B		3.0	3.5	4.0	ns
tsk(b)	Bank Skew; NOTE 2, 6		Measured on the Rising Edge			50	ps
tsk(o)	Output Skew; NOTE 3, 6		Measured on the Rising Edge			170	ps
tsk(pp)	Part-to-Part Sk	ew; NOTE 4, 6				800	ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fa	all Time; NOTE 5	20% to 80%	200		700	ps
ada	Output Duty O	vala.	<i>f</i> < 175MHz	45		55	%
odc	Output Duty Cycle		<i>f</i> ≥ 175MHz	40		60	%
t <sub>EN</sub>	Output Enable Time; NOTE 5					10	ns
t <sub>DIS</sub>	Output Disable	Time; NOTE 5				10	ns

All parameters measured at 250MHz unless noted otherwise.

NOTE 1A: Measured from the  $V_{DD}/2$  of the input to  $V_{DDOX}/2$  of the output.

NOTE 1B: Measured from the differential input crossing point to V<sub>DDOX</sub>/2 of the output.

NOTE 2: Defined as skew within a bank with equal load conditions.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at  $V_{DDOX}/2$ .

NOTE 4: Defined as skew between outputs on different devices operating a the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at  $V_{DDOX}/2$ .

NOTE 5: These parameters are guaranteed by characterization. Not tested in production.

NOTE 6: This parameter is defined in accordance with JEDEC Standard 65.

Table 5D. AC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDOx} = 1.8V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$ 

Parameter	Symbol		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Frequency					250	MHz
to	Propagation	CLK0; NOTE 1A		3.0	3.9	4.7	ns
tp <sub>LH</sub>	LOW LO I HUH	CLK1/CLK1; NOTE 1B		3.0	3.9	4.7	ns
tsk(b)	Bank Skew; NOTE 2, 6		Measured on the Rising Edge			50	ps
tsk(o)	Output Skew; NOTE 3, 6		Measured on the Rising Edge			170	ps
tsk(pp)	Part-to-Part Sk	ew; NOTE 4, 6				800	ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fa	all Time; NOTE 5	20% to 80%	200		700	ps
odc	Output Duty C	volo	<i>f</i> < 175MHz	45		55	%
ouc	Output Duty Cycle		<i>f</i> ≥ 175MHz	40		60	%
t <sub>EN</sub>	Output Enable Time; NOTE 5					10	ns
t <sub>DIS</sub>	Output Disable	Time; NOTE 5				10	ns

For NOTES, please see above, Table 5C.

Table 5E. AC Characteristics,  $V_{DD}$  = 2.5V  $\pm$  5%,  $V_{DDOx}$  = 1.8V  $\pm$  5%,  $T_A$  = -40°C to 85°C

Parameter	Symbol Output Frequency		Test Conditions	Minimum	Typical	Maximum 250	Units MHz
f <sub>MAX</sub>							
tp <sub>LH</sub>	Propagation Delay, Low to High	CLK0; NOTE 1A		3.1	4.1	5.2	ns
		CLK1/CLK1; NOTE 1B		3.0	3.9	4.7	ns
tsk(b)	Bank Skew; NOTE 2, 6		Measured on the Rising Edge			70	ps
tsk(o)	Output Skew; NOTE 3, 6		Measured on the Rising Edge			210	ps
tsk(pp)	Part-to-Part Skew; NOTE 4, 6					800	ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time; NOTE 5		20% to 80%	150		700	ps
odc	Output Duty Cycle		<i>f</i> < 175MHz	45		55	%
			<i>f</i> ≥ 175MHz	40		60	%
t <sub>EN</sub>	Output Enable Time; NOTE 5					10	ns
t <sub>DIS</sub>	Output Disable Time; NOTE 5					10	ns

All parameters measured at 250MHz unless noted otherwise.

NOTE 1A: Measured from the  $V_{DD}/2$  of the input to  $V_{DDOX}/2$  of the output.

NOTE 1B: Measured from the differential input crossing point to V<sub>DDOX</sub>/2 of the output.

NOTE 2: Defined as skew within a bank with equal load conditions.

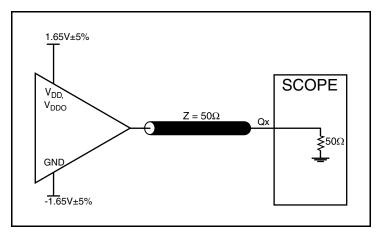
NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at VDDOX/2.

NOTE 4: Defined as skew between outputs on different devices operating a the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at  $V_{DDOX}/2$ .

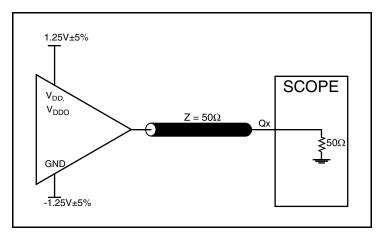
NOTE 5: These parameters are guaranteed by characterization. Not tested in production.

NOTE 6: This parameter is defined in accordance with JEDEC Standard 65.

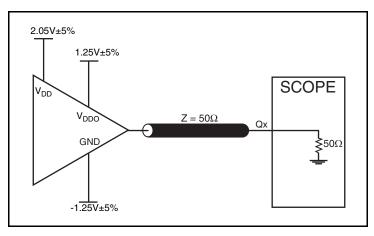
### **Parameter Measurement Information**



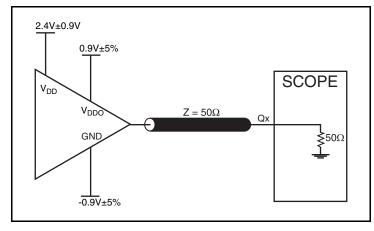
3.3V Core/3.3V LVCMOS Output Load Test Circuit



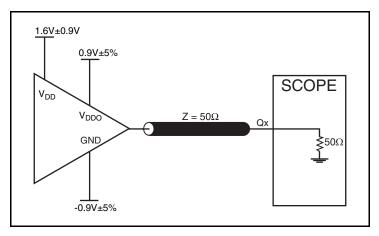
2.5V Core/2.5V LVCMOS Output Load Test Circuit



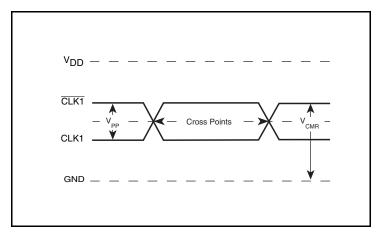
3.3V Core/2.5V LVCMOS Output Load Test Circuit



3.3V Core/1.8V LVCMOS Output Load Test Circuit

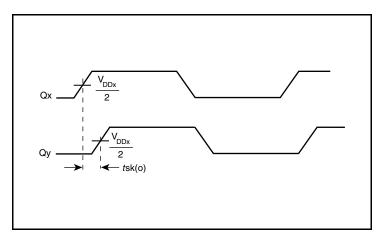


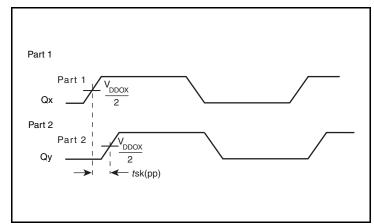
2.5V Core/1.8V LVCMOS Output Load Test Circuit



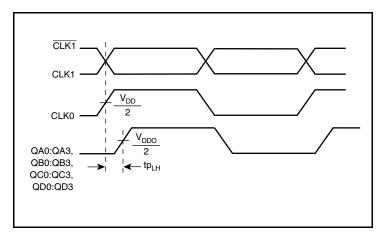
**Differential Input Level** 

# **Parameter Measurement Information, continued**

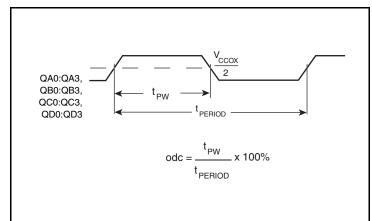




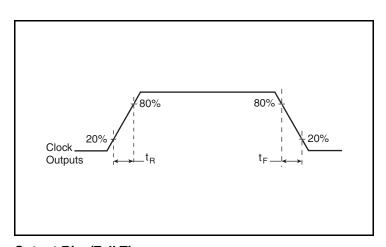
**Output Skew** 



**Part-to-Part Skew** 



**Propagation Delay** 



**Output Duty Cycle/Pulse Width/Period** 

**Output Rise/Fall Time** 

# **Application Information**

#### Wiring the Differential Input to Accept Single Ended Levels

Figure 1 shows how the differential input can be wired to accept single ended levels. The reference voltage  $V_REF = V_{DD}/2$  is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the  $V_REF$  in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and  $V_{DD} = 3.3V$ ,  $V_REF$  should be 1.25V and R2/R1 = 0.609.

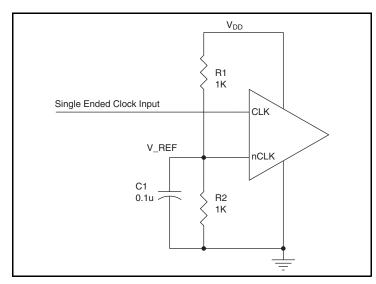


Figure 1. Single-Ended Signal Driving Differential Input

#### **Recommendations for Unused Input and Output Pins**

#### Inputs:

#### **CLK/CLK** Inputs:

For applications not requiring the use of the differential input, both CLK and  $\overline{\text{CLK}}$  can be left floating. Though not required, but for additional protection, a 1k $\Omega$  resistor can be tied from CLK to ground.

### **CLK Input:**

For applications not requiring the use of a clock input, it can be left floating. Though not required, but for additional protection, a  $1 k\Omega$  resistor can be tied from the CLK input to ground.

#### **LVCMOS Control Pins:**

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A  $1k\Omega$  resistor can be used.

#### **Outputs:**

#### **LVCMOS Outputs:**

All unused LVCMOS output can be left floating. There should be no trace attached.

### **Differential Clock Input Interface**

The CLK /CLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both signals must meet the V<sub>PP</sub> and V<sub>CMR</sub> input requirements. *Figures 2A to 2E* show interface examples for the CLK/CLK input driven by the most common driver types. The input interfaces suggested here are examples only. Please consult with the

vendor of the driver component to confirm the driver termination requirements. For example, in Figure 2A, the input termination applies for IDT LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

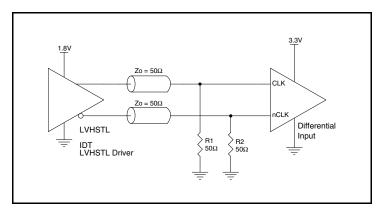


Figure 2A. CLK/CLK Input Driven by an IDT LVHSTL Driver

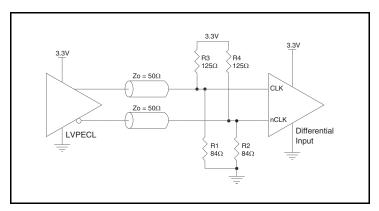


Figure 2C. CLK/CLK Input Driven by a 3.3V LVPECL Driver

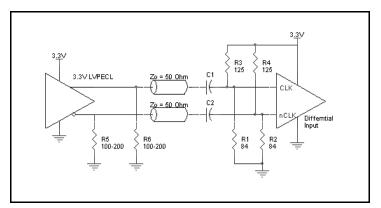


Figure 2E. CLK/CLK Input Driven by a 3.3V LVPECL Driver with AC Couple

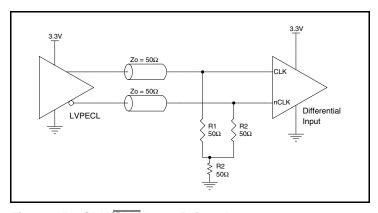


Figure 2B. CLK/CLK Input Driven by a 3.3V LVPECL Driver

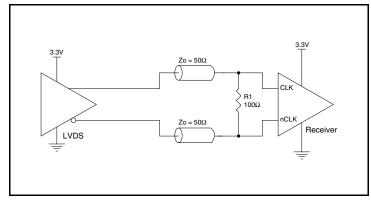


Figure 2D. CLK/CLK Input Driven by a 3.3V LVDS Driver

# **Reliability Information**

Table 6.  $\theta_{\mbox{\scriptsize JA}}$  vs. Air Flow Table for a 48 Lead LQFP

$\theta_{JA}$ vs. Air Flow				
Linear Feet per Minute	0	200	500	
Single-Layer PCB, JEDEC Standard Test Boards	67.8°C/W	55.9°C/W	50.1°C/W	
Multi-Layer PCB, JEDEC Standard Test Boards	47.9°C/W	42.1°C/W	39.4°C/W	

NOTE: Most modern PCB design use multi-layered boards. The data in the second row pertains to most designs.

#### **Transistor Count**

The transistor count for ICS87016I is: 2034

# **Package Outline and Package Dimension**

# Package Outline - Y Suffix for 48 Lead LQFP

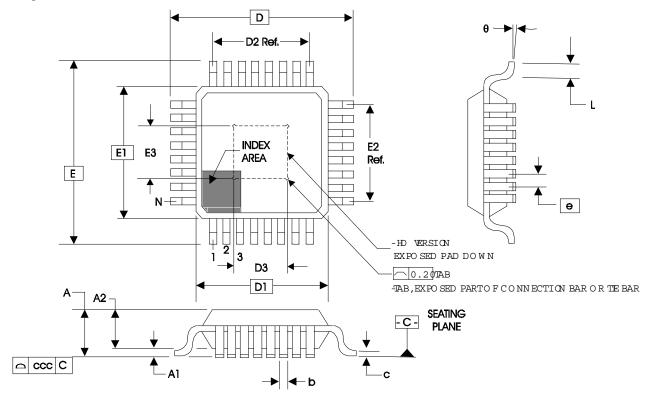


Table 7. Package Dimensions for 48 Lead LQFP

JEDEC Variation: ABC - HD All Dimensions in Millimeters				
Symbol	Minimum	Nominal	Maximum	
N	48			
Α			1.20	
A1	0.05	0.10	0.15	
A2	0.95	1.00	1.05	
b	0.17	0.22	0.27	
С	0.09		0.20	
D&E	9.00 Basic			
D1 & E1	7.00 Basic			
D2 & E2	5.50 Ref.			
D3 & E3	2.0		7.0	
е	0.5 Basic			
L	0.45	0.60	0.75	
θ	0°		7°	
ccc			0.08	

Reference Document: JEDEC Publication 95, MS-026

# **Ordering Information**

# **Table 8. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
ICS87016AYILF	TBD	"Lead-Free" 48 Lead LQFP	Tray	-40°C to 85°C
ICS87016AYILFT	TBD	"Lead-Free" 48 Lead LQFP	Tape & Reel	-40°C to 85°C

# **Revision History Sheet**

Rev	Table	Page	Description of Change	
В	T2 T4B T4C T4D T5B T5E	1 3 4 5 5 6 8 9	Features Section - added 2.5V/2.5V and 2.5V/1.8V to supply mode bullet. Added lead-free bullet Pin Characteristics Table - added 2.5V/2.5V and 2.5V/1.8V to C <sub>PD</sub> . Added 2.5V Power Supply DC Characteristics Table. LVCMOS DC Characteristics Table - added 2.5V to V <sub>IH</sub> /V <sub>IL</sub> . Differential DC Characteristics Table - added 2.5V to I <sub>IH</sub> /I <sub>IL</sub> . Added 2.5V Power Supply DC Characteristics Table. Added 2.5V/1.8V Power Supply DC Characteristics Table. Parameter Measurement Information - added 2.5V Core/2.5V Output Load Test Circuit and 2.5V Core/1.8V Output Load Test Circuit diagrams. Added Recommendations for Unused Input and Output Pins. Ordering Information Table - added lead-free Order/Part Number.	3/30/07
С	T5B	6	2.5V AC Characteristics Table - changed <i>Output Duty Cycle</i> test condition and limits. Added Output Pulse Width.	5/25/07
С	Т8	15	Remove leaded parts from Ordering Information table	11/15/12
С	4C	5	Corrected typo, VOH: V <sub>DD</sub> – 0.45 to V <sub>DDOx</sub> – 0.45	3/28/13

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6024 Silver Creek Valley Road San Jose, California 95138

Sales

800-345-7015 (inside USA) +408-284-8200 (outside USA) Fax: 408-284-2775 www.IDT.com/go/contactIDT **Technical Support Sales** 

netcom@idt.com +480-763-2056

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